

TLV IN LUND

Introduction to Top Level Verification

PRESENTER



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- B.Sc.E. in Computer Engineering (Engineering College of Copenhagen 2004)
- M. SC. EE. In “System on Chip” (LTH 2006)
- Work experience
 - › EMP 2006 – 2009
 - › ST-Ericsson 2009 – 2013
 - › Ericsson 2013 -
- Verification Engineer

ERICSSON IN LUND



- › Radio Product and variant Lund
 - Radio, analog and mix signals ASICs for 5G
 - FPGA Products
 - Design & Verification in all levels
- › SOC Level I&V
 - Top Level Verification for Radio ASICs

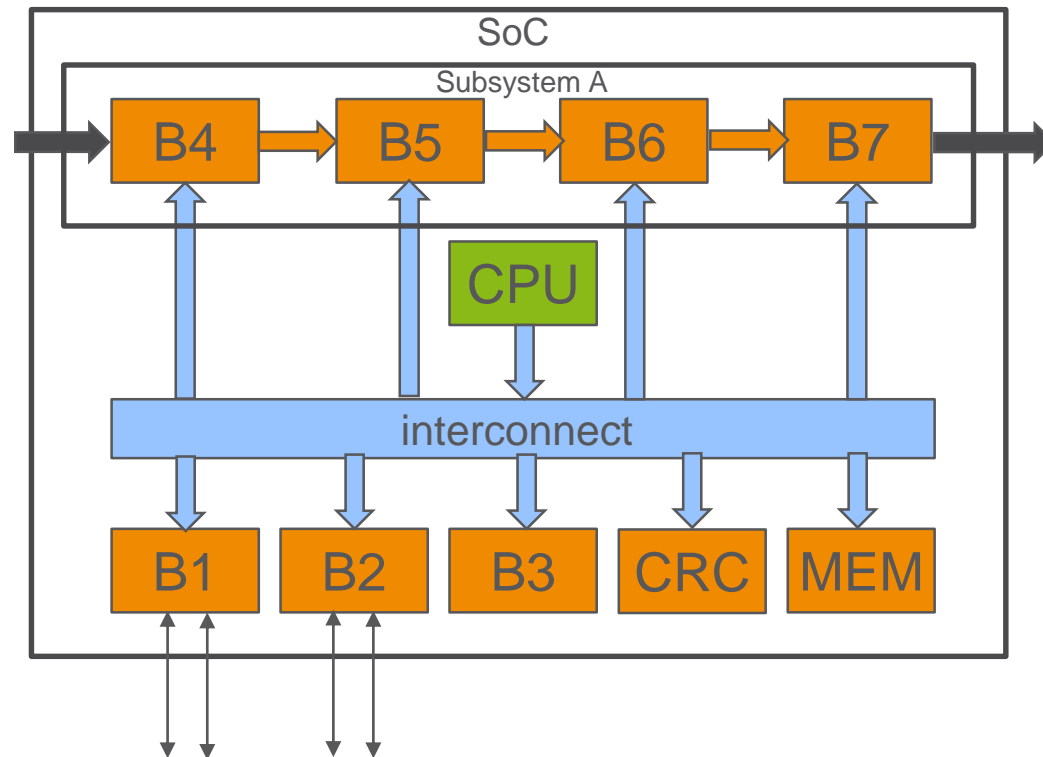
AGENDA



Top Level Verification in focus

- › **SoC Verification**
- › What do we do?
- › TLV SW environment
- › Why Verification?
- › TLV in other areas
- › Q&A

SoC



VERIFICATION SCOPES



› Block Verification

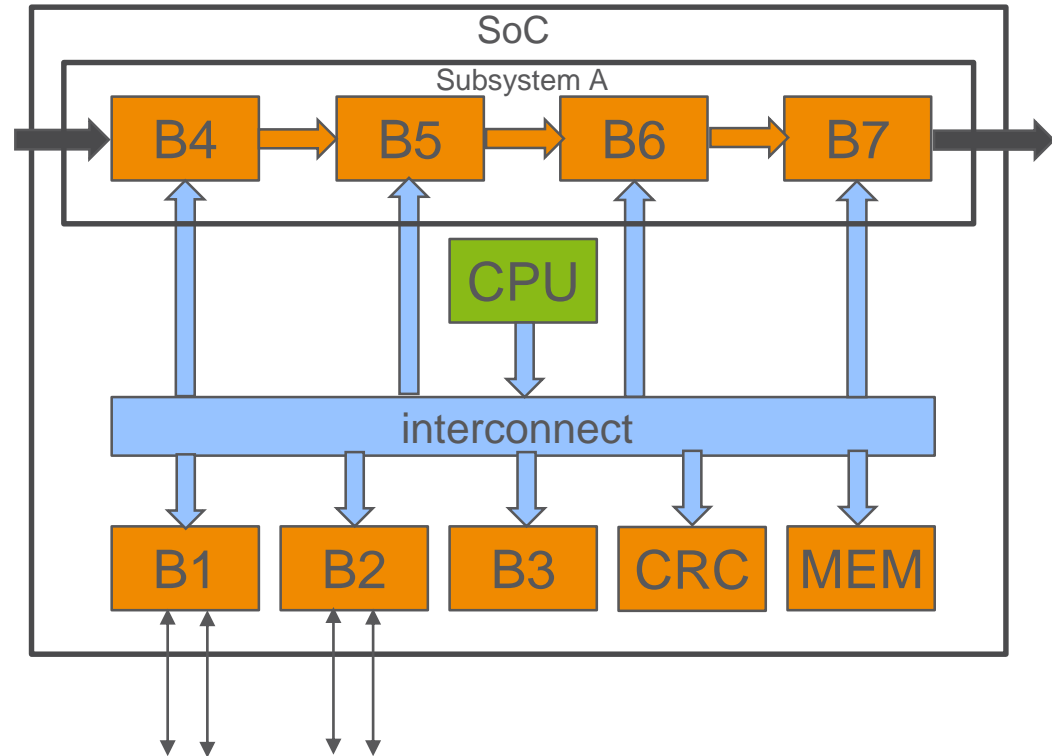
- Block functionality
- Protocol verification
- Full coverage e.g. code coverage

› Subsystem Verification

- Integration of blocks
- Functionality of combined blocks

› Top Level Verification

- Integration test
- Functional test of full system
- Pad verification



TLV MISSION



- › Full responsibility for the functionality of the ASIC/SoC
- › Design implemented according to the Specification
- › Involved in ASIC Bring up activities

AGENDA



- › SoC Verification
- › **What do we do?**
- › TLV SW environment
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WHAT DO WE DO?



› Project start

- Workshop and information meetings
- Verification Planning
- Prepare SW and TB environment for the Project
- CPU architecture and compiler
 - › ARM CA53, CA9, CA7, CA5
 - › ARM CM4, CM7
 - › ARM CR4

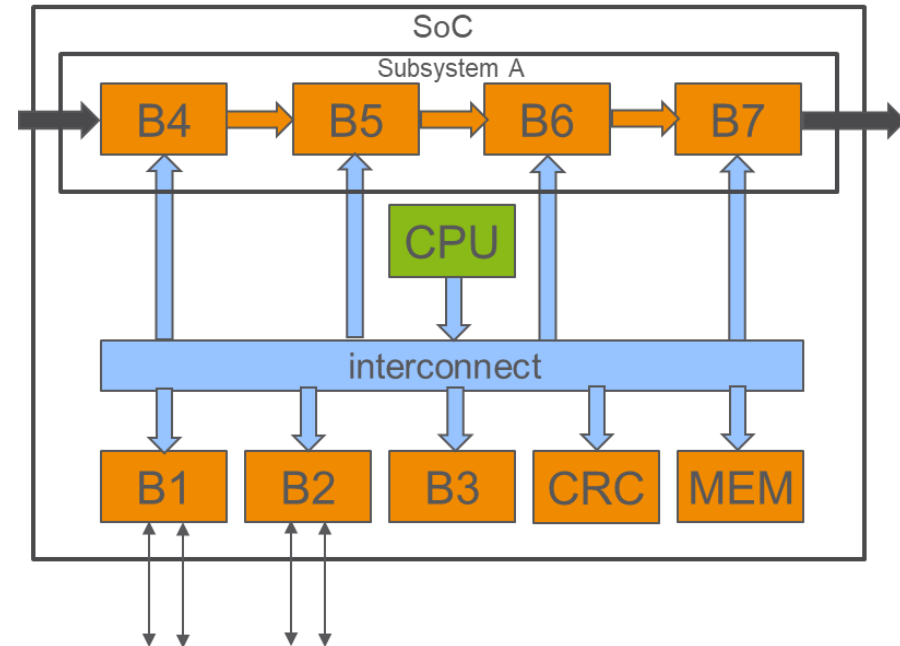


WHAT DO WE DO?



› Sanity test

- Boot all CPUs and Cores
 - › Clk & rst, Memories, Interconnect
- Interconnect test
 - › Access every block into the system, one register on every block
- Memory test
 - › Access memories, few locations

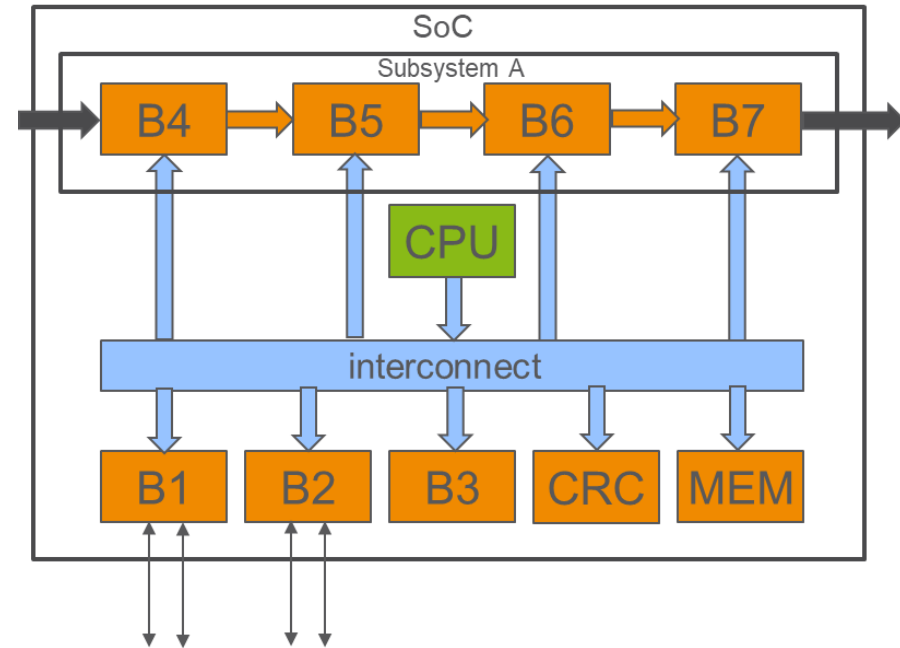


WHAT DO WE DO?



› Integration test

- Integration test of Blocks with external interfaces (B1, B2)
 - › E.g. UART, I2C, DDR
- Integration test of internal blocks (B3)
 - › E.g. Timer, Interrupt controller
- Integration test of Subsystems (SubSys A)
 - › Verify all interfaces of the subsystem

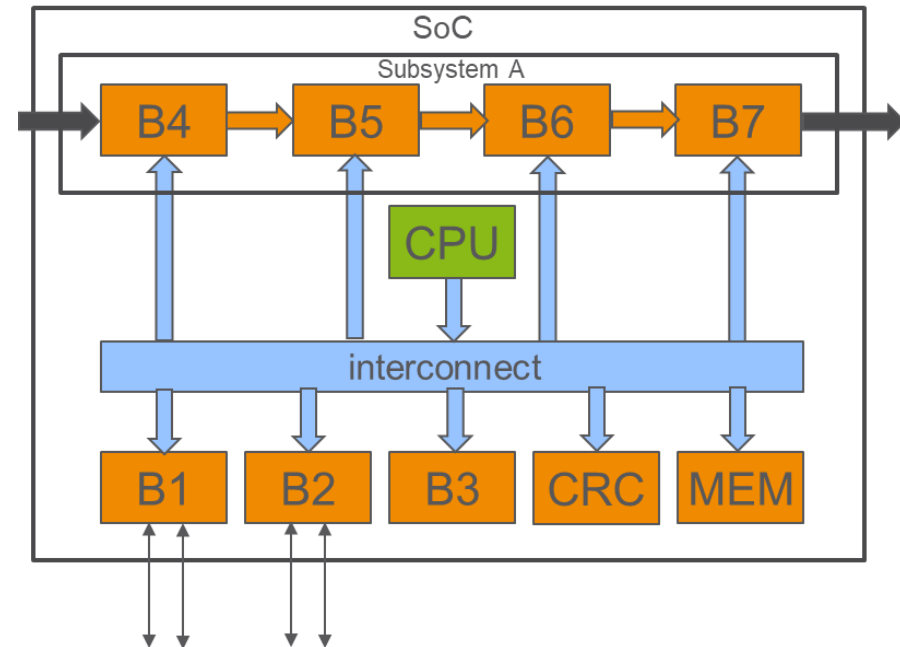


WHAT DO WE DO?



> Functional test

- Functional test of complex blocks
 - > Complement to Integration test
- Functional use cases including several blocks
 - > Different complexity levels
- All supported boot modes
- Cold and warm reset logic
- Clock tree verification



WHAT DO WE DO?

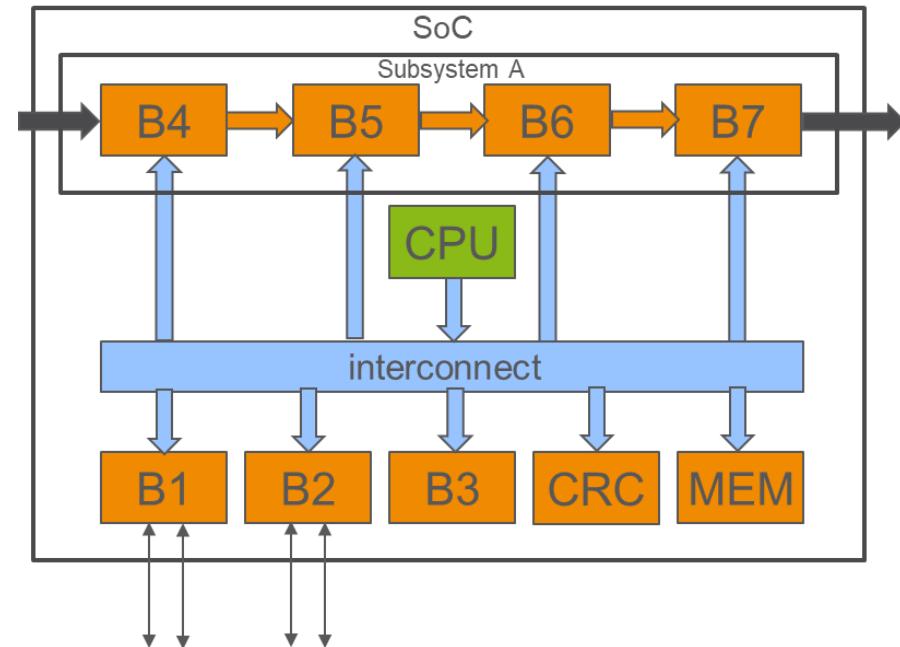


› Netlist Simulations

- Run simple tests on the synthesized netlist
- Without and with SDF (Timing information)

› Regression Run

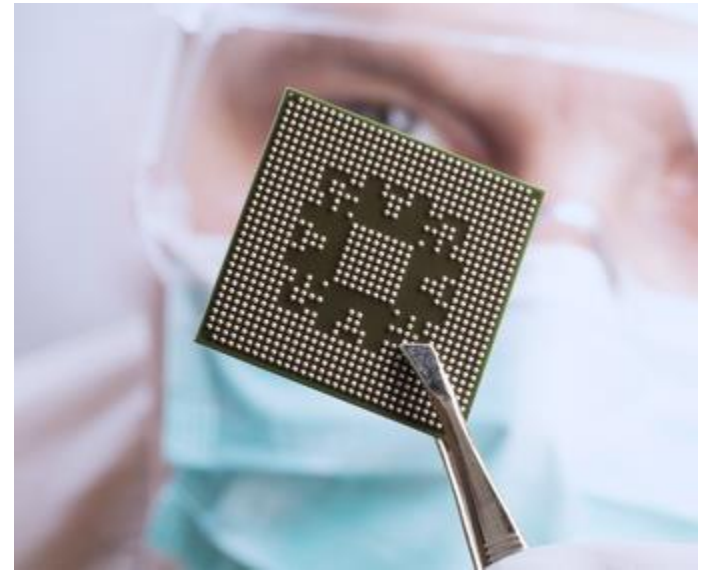
- Rerun all the tests in Regression mode
- Quality stamp before "tape out"



WHAT DO WE DO?



- › ASIC Bring up
 - Run tests on the Silicon after production
 - Verify package
 - Sanity test of all external interfaces
- › Support SW community in getting up to speed
 - Help debug HW related issues



AGENDA



- › SoC Verification
- › What do we do?
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SW DRIVEN VERIFICATION



- › The SW driven flow uses the existing cores in the DUT to verify the integration and/or functionality of the design
- › Using SW the system is verified as it is intended to be used
- › Since the test cases are implemented in SW they can easily be reused on different platforms
 - Virtual Platforms
 - Emulation
 - RTL Simulation
 - ASIC Bring-Up
- › Directed tests are primarily used in the SW driven flow
 - Exhaustive testing is more suitable for constrained random flows
 - But there are also tools available on the market that can auto generate parts of the SW => enable exhaustive testing using SW

TEST ARCHITECTURE



Flexible Architecture Software Test bench

› TEST SW

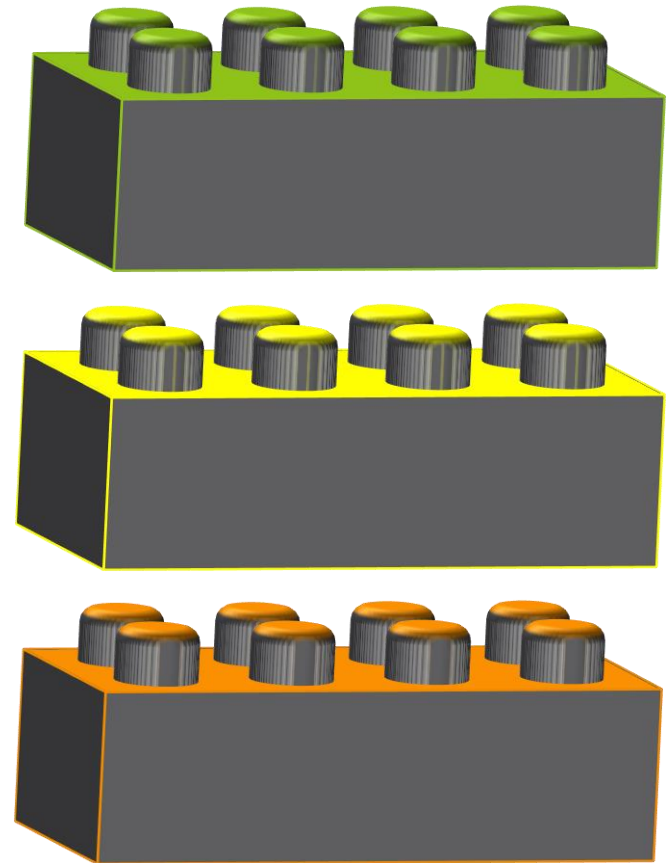
- Test SW including drivers and register mapping, in C.
- ELF and HEX files are generated to be loaded into the memories.

› TC specific TB files

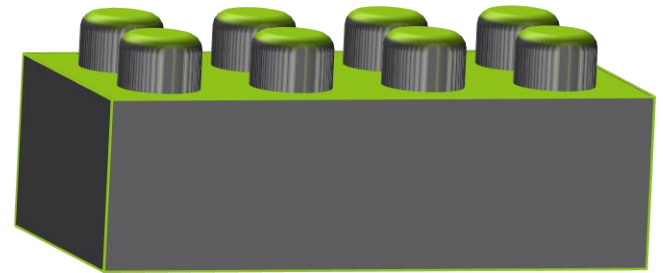
- Additional DUT connections
- Verification components
- Assertions
- Parameters and forces

› Common TB files

- DUT
- Standard TB components
- Optional external memories



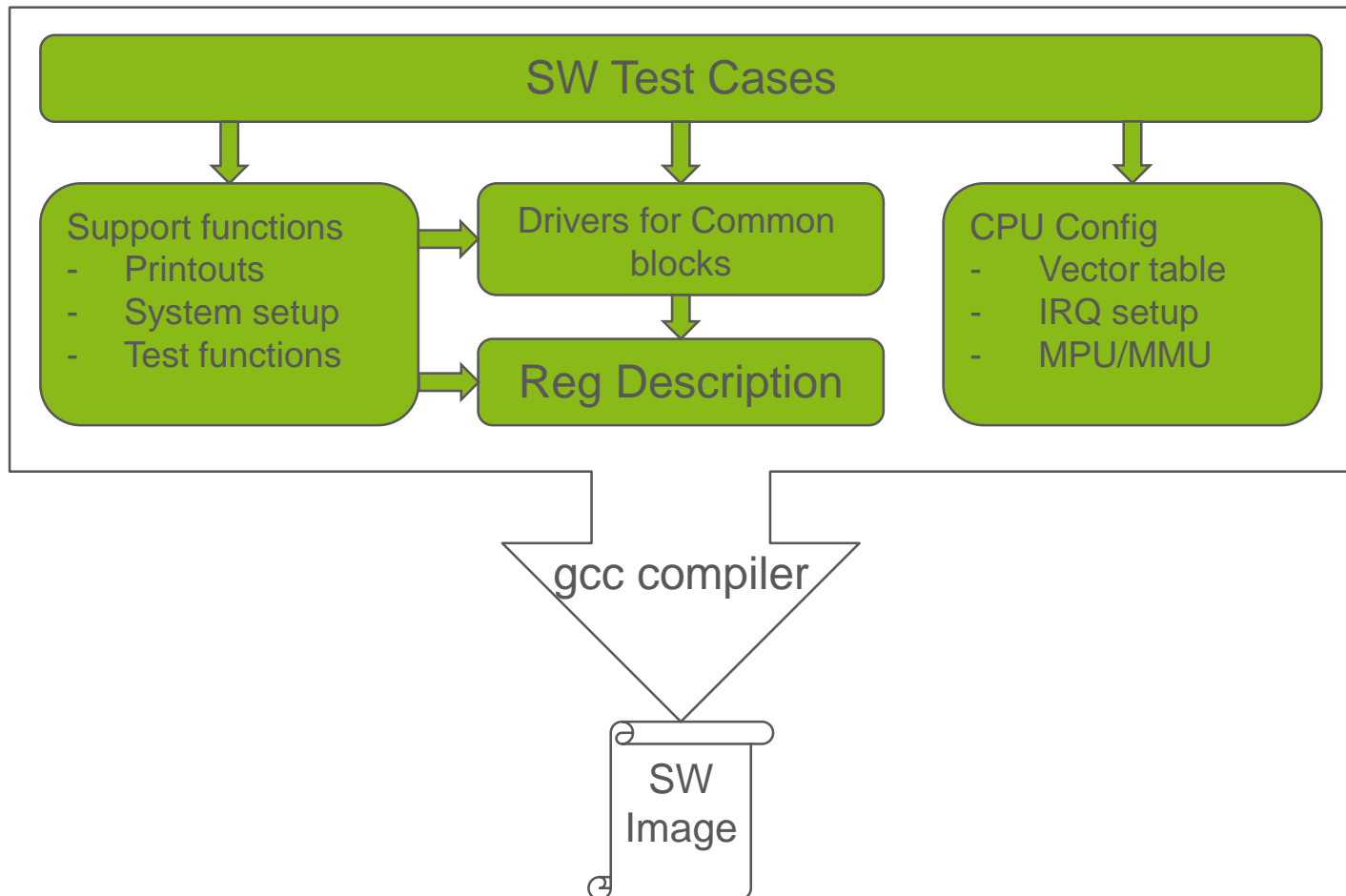
TEST SW



SW ARCHITECTURE



> C base SW



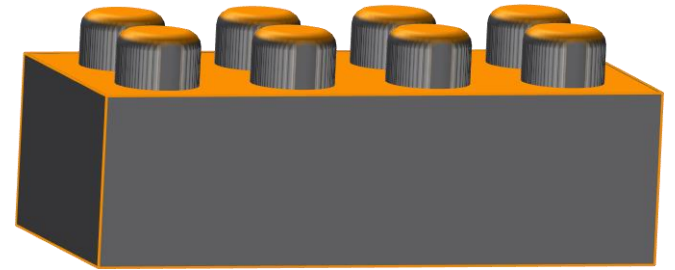
TEST CASES



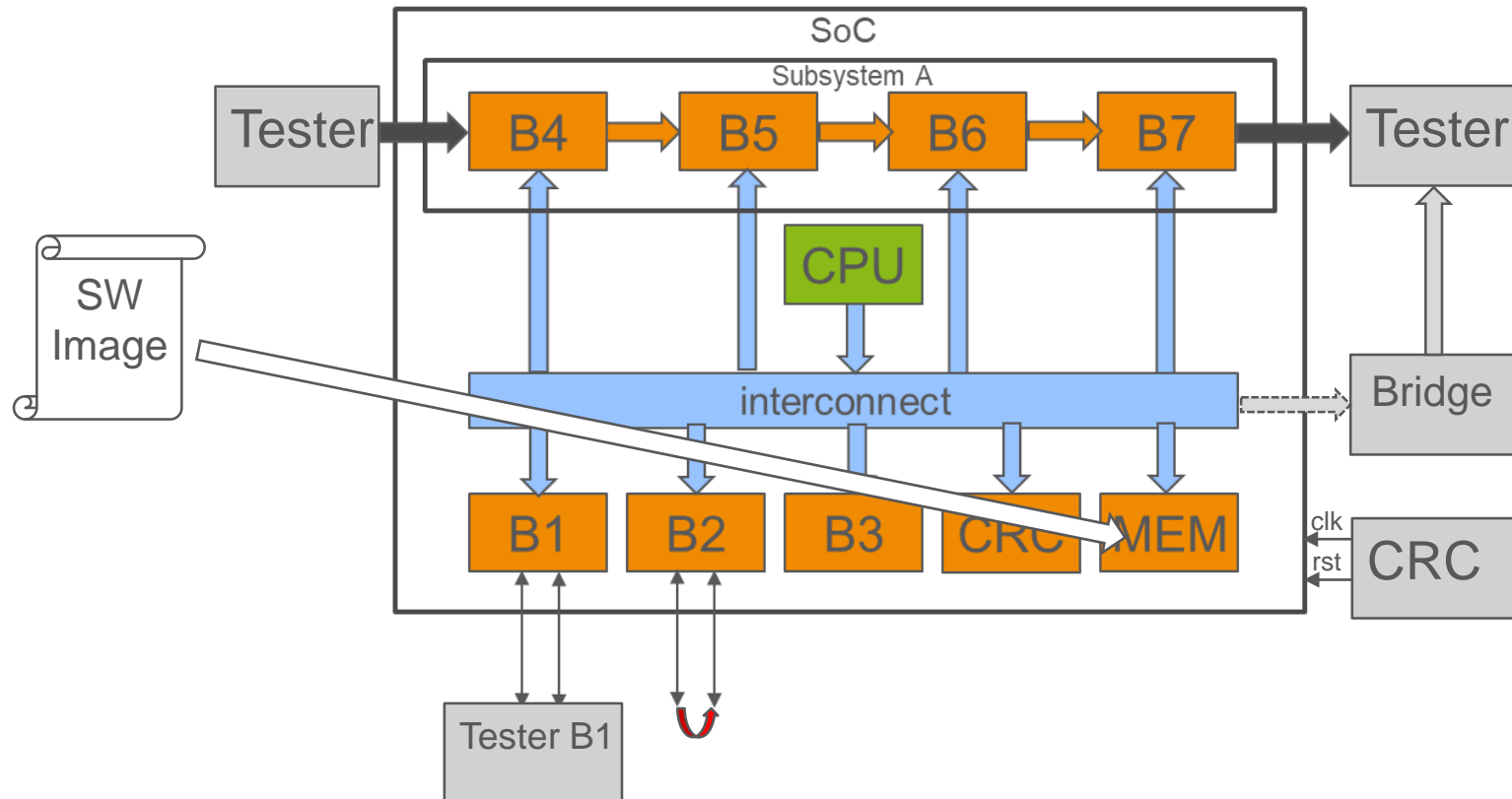
› TC categories

- Sanity – simple tests for sanity purpose (e.g. boot)
- Register – complete register test of a block
- Integration – Integration test of a block
- Function – complex functional tests of the one or more blocks or subsystem
- ABU – Sw test for ASIC bring up activities

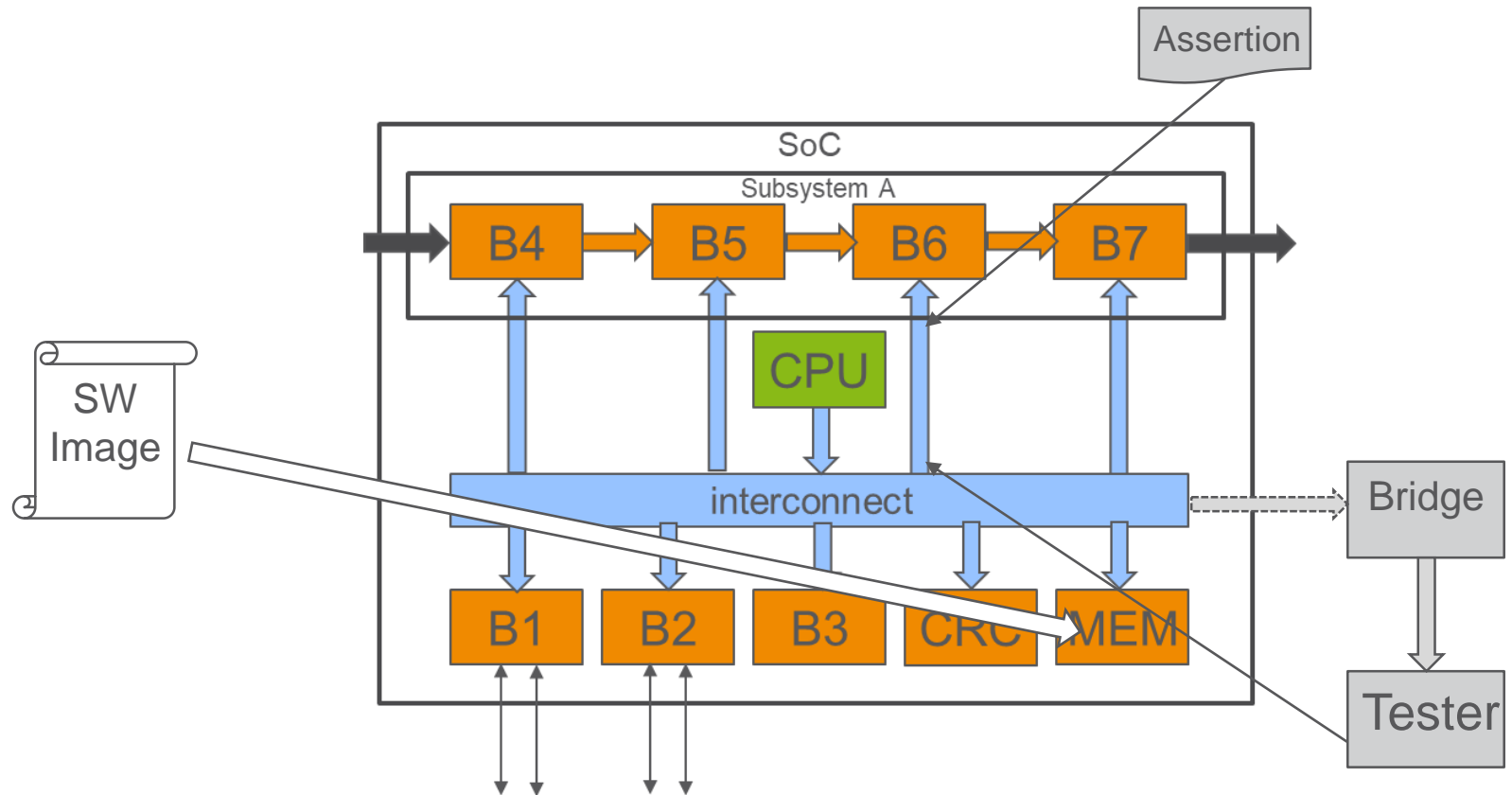
SW TESTBENCH



SW DRIVEN TB



INTEGRATION TEST WITH ASSERTION



DEBUG SW



- › How to debug the SW when running in simulation environment?
 - Printout!
 - › Printf vs. Costumized functions

```
printf("read data %d from memory\n", data);  
TST_REPORT_SNS("read data ", data, "from memory\n");
```
 - › UART vs Costumized Tester
 - Uart is slow in simulation
 - Use costumized test component with dedicated registers for printouts
 - ARM Tarmac log
 - › “Tarmac is a textual trace output. Fast Models supports the generation of traces that consistently track the execution and related activities in the model, particularly those that affect the state of the modeled IP.”

TARMAC LOG



› Tarmac log example

```
13799 ns ES (0000584a:4607) T thrd: MOV r7,r0 <TST_REPORT_SNS+0x2>
R R7 0000710c
13799 ns ES (0000584c:460e) T thrd: MOV r6,r1 <TST_REPORT_SNS+0x4>
R R6 00000000
13801 ns ES (0000584e:4615) T thrd: MOV r5,r2 <TST_REPORT_SNS+0x6>
R R5 00007be0
13801 ns ES (00005850:461c) T thrd: MOV r4,r3 <TST_REPORT_SNS+0x8>
R R4 00000002
13803 ns ES (00005852:b933) T thrd: CBNZ r3,{pc}+0x10 ; 0x5862 <TST_REPORT_SNS+0xa>
BR (00005862) T
13815 ns ES (00005862:4621) T thrd: MOV r1,r4 <TST_REPORT_SNS+0x1a>
R R1 00000002
13815 ns ES (00005864:4638) T thrd: MOV r0,r7 <TST_REPORT_SNS+0x1c>
R R0 0000710c
13817 ns ES (00005866:f00fd4d) T thrd: BL {pc}+0xa9e ; 0x6304 <TST_REPORT_SNS+0x1e>
R LR 0000586b
BR (00006304) T
13830 ns ES (00006304:b5f0) T thrd: PUSH {r4-r7,lr} <TST_STDIO_STRING>
ST 2000fe90 ..... 0000586b 0000710c
ST 2000fe80 00000000 00007be0 00000002 .....
R SP (Main) 2000fe84
13832 ns ES (00006306:b085) T thrd: SUB sp,sp,#0x14 <TST_STDIO_STRING+0x2>
R SP (Main) 2000fe70
13832 ns ES (00006308:4605) T thrd: MOV r5,r0 <TST_STDIO_STRING+0x4>
R R5 0000710c
13834 ns ES (0000630a:460e) T thrd: MOV r6,r1 <TST_STDIO_STRING+0x6>
R R6 00000002
13834 ns ES (0000630c:4b3d) T thrd: LDR r3,{pc}+0xf8 ; 0x6404 <TST_STDIO_STRING+0x8>
LD 00006400 ..... 806ff000 .....
R R3 806ff000
13856 ns ES (0000630e:681c) T thrd: LDR r4,[r3,#0] <TST_STDIO_STRING+0xa>
LD 806ff000 ..... 00000000
R R4 00000000
13858 ns ES (00006310:3403) T thrd: ADDS r4,#3 <TST_STDIO_STRING+0xc>
R R4 00000003
```

SW DEBUGGER



The screenshot displays the SW Debugger interface with three main panels:

- Source Viewer:** Shows the source code of `tl1_simctrl.c` and `tst_report.c`. The current line of execution is highlighted at address 21036.
- Registers:** A table showing the current state of registers. The XPSR register is highlighted with a value of `'h1000000'`.
- Waveform - SimVision:** A timeline view showing the execution of the program. The current time is 181,719 ns. The waveform shows the execution of the `TST_REPORT_SNS` function.

The Registers panel contains the following data:

Name	Value
R0	'h7d9c'
R1	'h0'
R2	'h7be0'
R3	'h2'
R4	'h2'
R5	'h7be0'
R6	'h0'
R7	'h7d9c'
R8	'h2'
R9	'h7ebc'
R10	'h7c04'
R11	'h0'
R12	'h200003c4'
R13	'h2000ff28'
R14	'h4597'
XPSR	'h1000000'

AGENDA

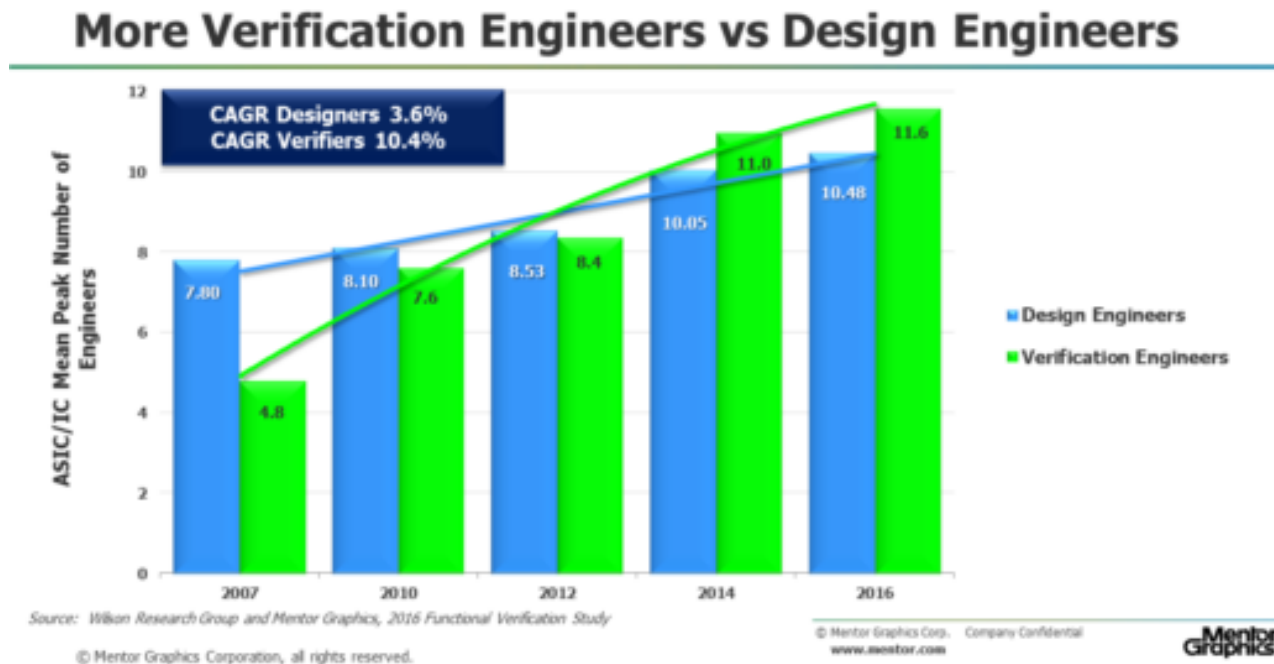


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INCREASING DEMAND



- › The 2016 Wilson Research Group Functional Verification Study

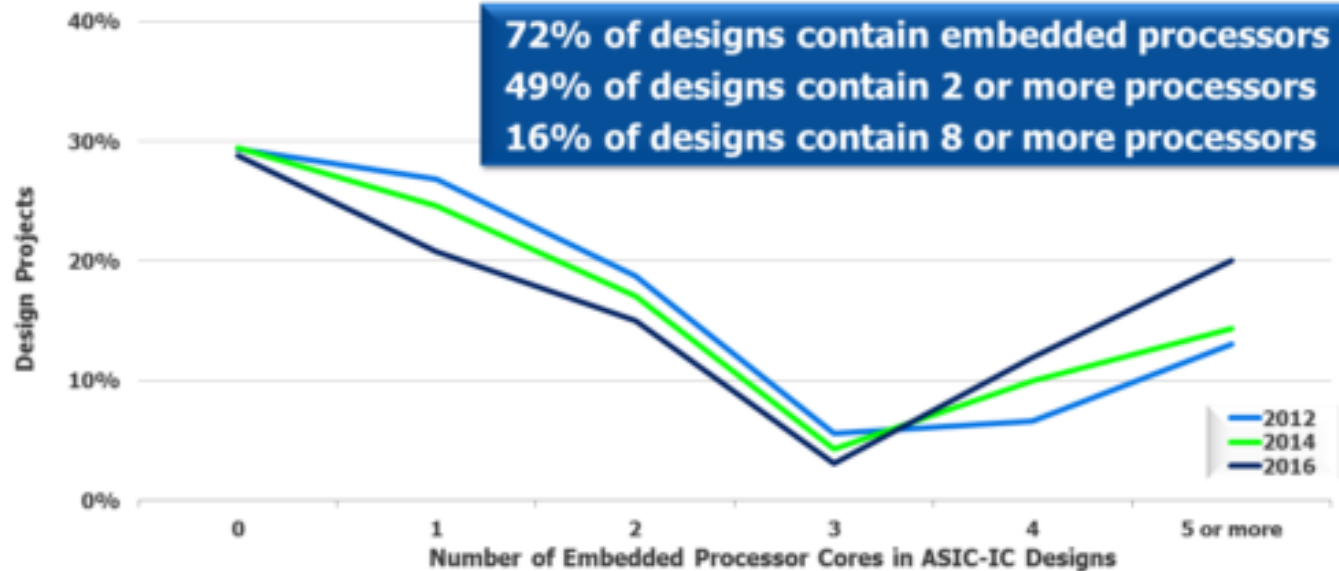


Source: <https://blogs.mentor.com/verificationhorizons/blog/2016/10/04/part-8-the-2016-wilson-research-group-functional-verification-study/>

COMPLEX SOC



It's an SoC World



Source: Wilson Research Group and Mentor Graphics, 2016 Functional Verification Study

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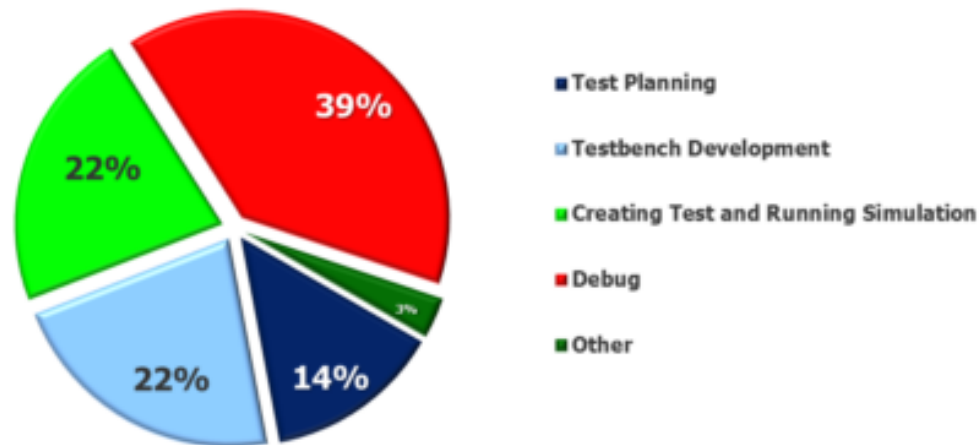
Source: <https://blogs.mentor.com/verificationhorizons/blog/2016/09/25/part-7-the-2016-wilson-research-group-functional-verification-study/>

TIMEPLAN



Where ASIC/IC Verification Engineers Spend Their Time

2016 Where ASIC/IC Verification Engineers Spend Their Time



Source: Wilson Research Group and Mentor Graphics, 2016 Functional Verification Study

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Source: <https://blogs.mentor.com/verificationhorizons/blog/2016/10/04/part-8-the-2016-wilson-research-group-functional-verification-study/>

WORKING IN TLV



- › Interesting
 - Different blocks and tools
- › Challenging
 - Complex functionality
- › Big responsibly
 - Responsible for the functionality of a "very" expensive product
- › Variation
 - Long project with various work packages
 - Work with both SW & HW

AGENDA

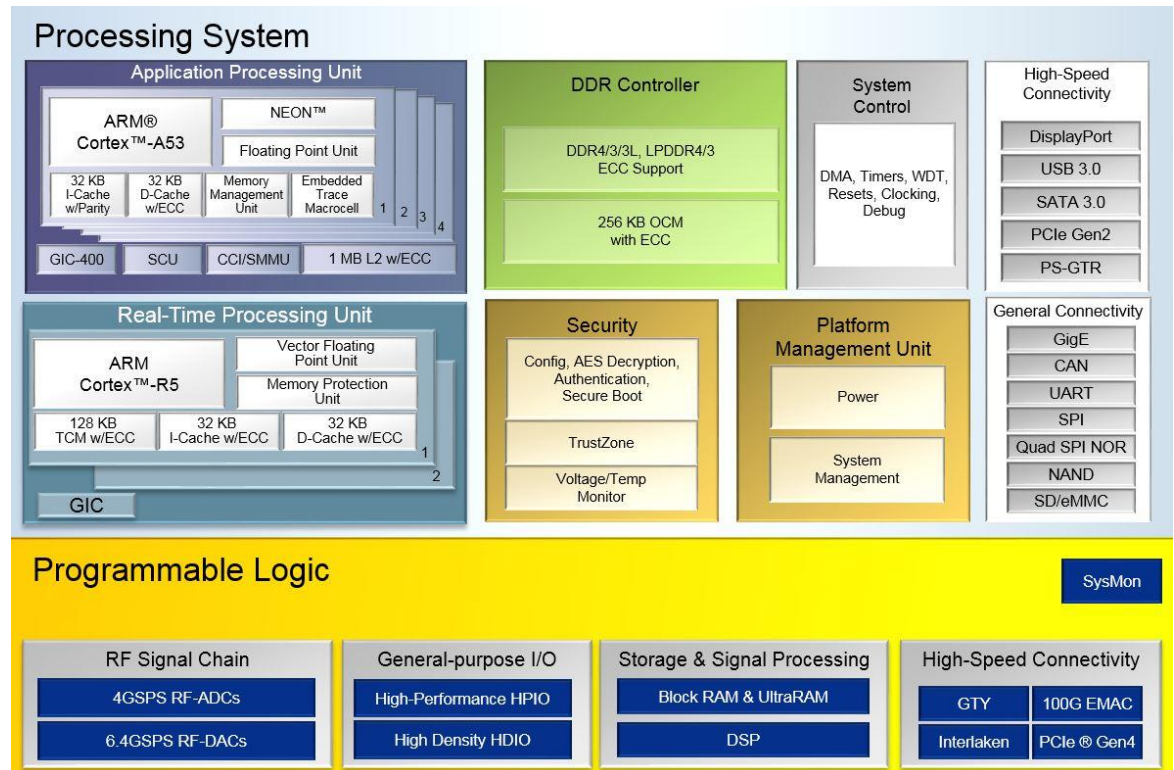


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SW DRIVEN ON FPGA



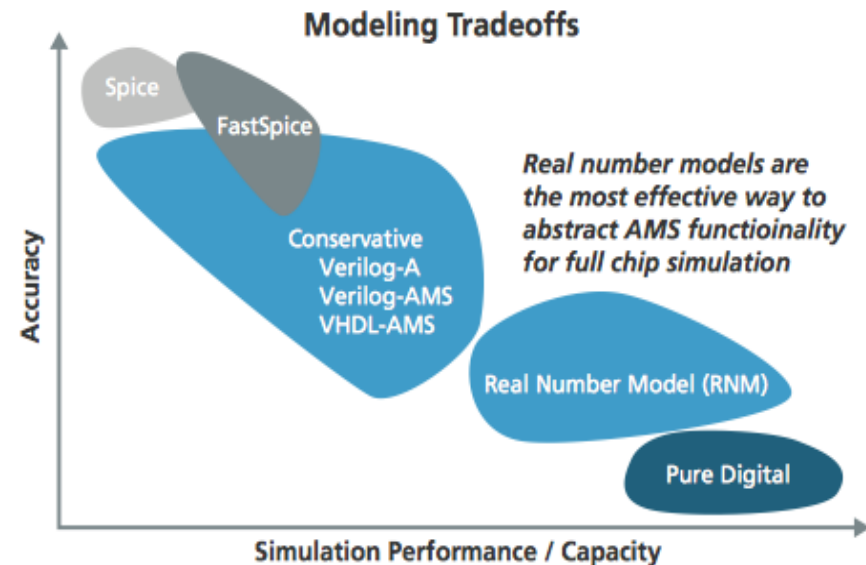
- › SoC on FPGAs
 - Zynq UltraScale from Xilinx
- › Reuse between Simulation and Lab environment



MIX SIGNAL ASIC



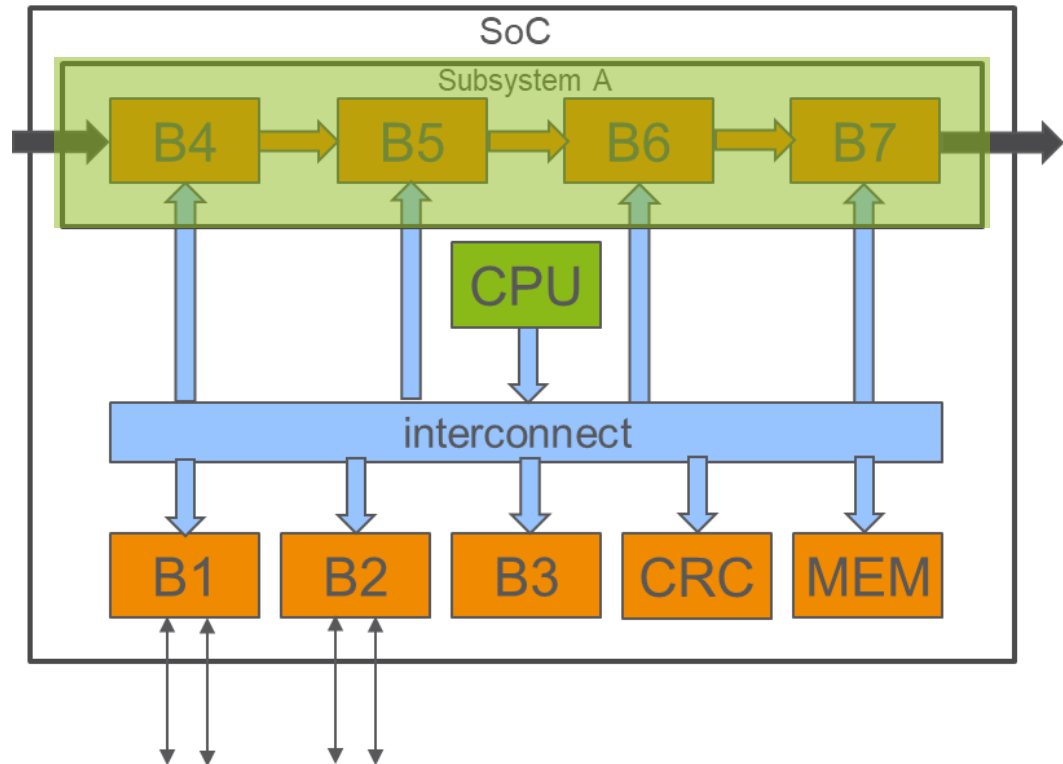
- › Combined analog and digital design
- › Perfect solution
 - SPICE + RTL simulations
 - Very slow or not possible due to complexity
- › Use model for analog design
 - Real Number Modeling RNM
 - SystemVerilog SV-RNM
 - › Supported by IEEE 1800-2012



POWER AWARE



- › Different power regions
- › Isolation between the regions
- › Simulate with UPF flow



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